BLF888B; **BLF888BS**

UHF power LDMOS transistor Rev. 1 — 17 October 2011

Product data sheet

Product profile 1.

1.1 General description

A 650 W LDMOS RF power transistor for broadcast transmitter applications and industrial applications. The excellent ruggedness of this device makes it ideal for digital and analog transmitter applications.

Application information

RF performance at $V_{DS} = 50 \text{ V}$ unless otherwise specified.

Mode of operation	f	P _{L(AV)}	P _{L(M)}	Gp	ηD	IMD3	IMD _{shldr}	PAR
	(MHz)	(W)	(W)	(dB)	(%)	(dBc)	(dBc)	(dB)
RF performance in a common source 860 MHz narrowband test circuit								
2-tone, class-AB	$f_1 = 860$; $f_2 = 860.1$	250	-	21	46	-34	-	-
DVB-T (8k OFDM)	858	120	-	21	33	-	-31 <mark>11</mark>	8.2 [2]
RF performance in a	a common source 47	0 MHz to	860 M	Hz bro	oadba	and test	circuit	
DVB-T (8k OFDM)	858	120	-	20	32	-	-32 [<u>1]</u>	8.0 [2]

^[1] Measured [dBc] with delta marker at 4.3 MHz from center frequency.

1.2 Features and benefits

- Excellent ruggedness
- Optimum thermal behavior and reliability, R_{th(i-c)} = 0.15 K/W
- High power gain
- High efficiency
- Designed for broadband operation (470 MHz to 860 MHz)
- Internal input matching for high gain and optimum broadband operation
- Excellent reliability
- Easy power control
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

1.3 Applications

- Communication transmitter applications in the UHF band
- Industrial applications in the UHF band



^[2] PAR (of output signal) at 0.01 % probability on CCDF; PAR of input signal = 9.5 dB at 0.01 % probability on CCDF.

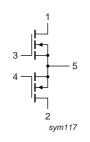
2. Pinning information

Table 2. Pinning

Pin	Description		Simplified outline	Graphic symbol
BLF888B	(SOT539A)			
1	drain1			
2	drain2		1 2	1
3	gate1		5	, F
4	gate2		3 4	3——5
5	source	<u>[1]</u>		4
				'ب
				2 sym117

BLF888BS (SOT539B)					
1	drain1				
2	drain2				
3	gate1				
4	gate2				
5	source	[1]			





[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BLF888B	-	flanged balanced LDMOST ceramic package; 2 mounting holes; 4 leads	SOT539A			
BLF888BS	-	earless flanged balanced LDMOST ceramic package; 4 leads	SOT539B			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	104	V
V_{GS}	gate-source voltage		-0.5	+11	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	200	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
R _{th(j-c)}	thermal resistance from junction to case	T_{case} = 80 °C; $P_{L(AV)}$ = 125 W	<u>[1]</u> 0.15	K/W

^[1] $R_{th(j-c)}$ is measured under RF conditions.

6. Characteristics

Table 6. DC characteristics

 $T_j = 25$ °C; per section unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 2.4 \text{ mA}$	[1]	104	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 240 \text{ mA}$	[1]	1.4	1.9	2.4	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V}$		-	-	2.8	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$		-	38	-	Α
I _{GSS}	gate leakage current	$V_{GS} = 10 \text{ V}; V_{DS} = 0 \text{ V}$		-	-	280	nΑ
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 8.5 \text{ A}$	[1]	-	120	-	mΩ
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz	[2]	-	210	-	pF
C _{oss}	output capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz		-	67	-	pF
C _{rss}	reverse transfer capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz		-	1.35	-	pF

^[1] I_D is the drain current.

Table 7. RF characteristics

RF characteristics in NXP production narrowband test circuit; $T_{case} = 25$ °C unless otherwise specified.

Currele el	Davamatav	Conditions		N#:	T	N/	I Incli
Symbol	Parameter	Conditions		IVIIN	Тур	Max	Unit
2-Tone, o	class-AB						
V_{DS}	drain-source voltage			-	50	-	V
I_{Dq}	quiescent drain current		[1]	-	1.3	-	Α
$P_{L(AV)}$	average output power	$f_1 = 860 \text{ MHz};$ $f_2 = 860.1 \text{ MHz}$		250	-	-	W
Gp	power gain	$f_1 = 860 \text{ MHz};$ $f_2 = 860.1 \text{ MHz}$		20	21	-	dB
η _D	drain efficiency	$f_1 = 860 \text{ MHz};$ $f_2 = 860.1 \text{ MHz}$		42	46	-	%
IMD3	third-order intermodulation distortion	$f_1 = 860 \text{ MHz};$ $f_2 = 860.1 \text{ MHz}$		-	-34	-30	dBc

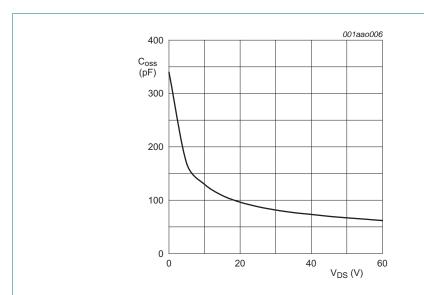
^[2] Capacitance values without internal matching.

 Table 7.
 RF characteristics ...continued

RF characteristics in NXP production narrowband test circuit; $T_{case} = 25$ °C unless otherwise specified.

0,00000							
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
DVB-T (8	k OFDM), class-AB						
V_{DS}	drain-source voltage			-	50	-	V
I _{Dq}	quiescent drain current		[1]	-	1.3	-	Α
$P_{L(AV)}$	average output power	f = 858 MHz		120	-	-	W
Gp	power gain	f = 858 MHz		20	21	-	dB
η_{D}	drain efficiency	f = 858 MHz		30	33	-	%
IMD_{shldr}	intermodulation distortion shoulder	f = 858 MHz	[2]	-	-31	-27	dBc
PAR	peak-to-average ratio	f = 858 MHz	[3]	-	8.2	-	dB

- [1] I_{dq} for total device
- [2] Measured [dBc] with delta marker at 4.3 MHz from center frequency.
- [3] PAR (of output signal) at 0.01 % probability on CCDF; PAR of input signal = 9.5 dB at 0.01 % probability on CCDF.



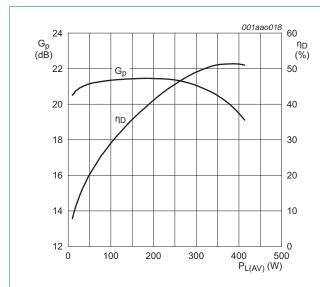
 $V_{GS} = 0 V$; f = 1 MHz.

Fig 1. Output capacitance as a function of drain-source voltage; typical values per section

7. Application information

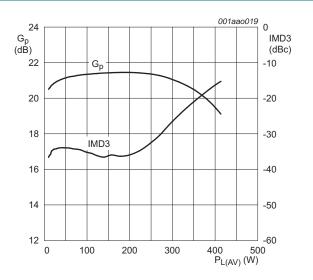
7.1 Narrowband RF figures

7.1.1 2-Tone



 $V_{DS} = 50 \; V; \; I_{Dq} = 1.3 \; A;$ measured in a common source narrowband 860 MHz test circuit.

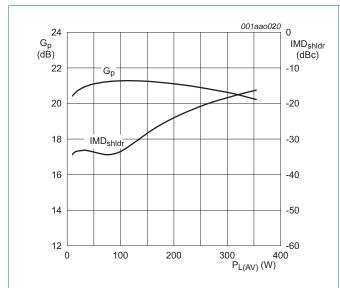
Fig 2. 2-Tone power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 50 \; V; \; I_{Dq} = 1.3 \; A;$ measured in a common source narrowband 860 MHz test circuit.

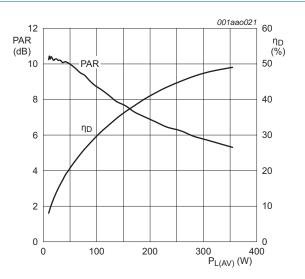
Fig 3. 2-Tone power gain and third order intermodulation distortion as load power; typical values

7.1.2 DVB-T



 V_{DS} = 50 V; I_{Dq} = 1.3 A; measured in a common source narrowband 860 MHz test circuit.

Fig 4. DVB-T power gain and intermodulation distortion shoulder as function of load power; typical values

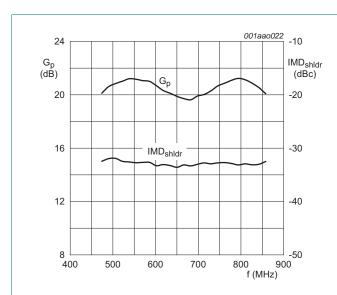


 V_{DS} = 50 V; I_{Dq} = 1.3 A; measured in a common source narrowband 860 MHz test circuit.

Fig 5. DVB-T peak-to-average ratio and drain efficiency as function of load power; typical values

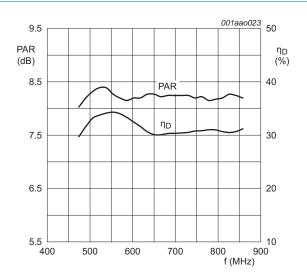
7.2 Broadband RF figures

7.2.1 DVB-T



 $P_{L(AV}$ =120 W; V_{DS} = 50 V; I_{Dq} = 1.3 A; measured in a common source broadband test circuit as described in Section 8.

Fig 6. DVB-T power gain and intermodulation distortion shoulder as function of frequency; typical values



 $P_{L(AV}$ =120 W; V_{DS} = 50 V; I_{Dq} = 1.3 A; measured in a common source broadband test circuit as described in Section 8.

Fig 7. DVB-T peak-to-average ratio and drain efficiency as function of frequency; typical values

BLF888B_BLF888BS

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7.3 Impedance information

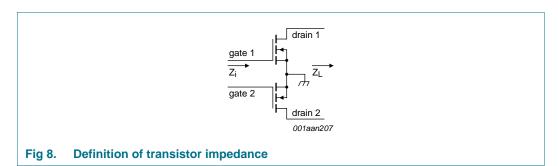
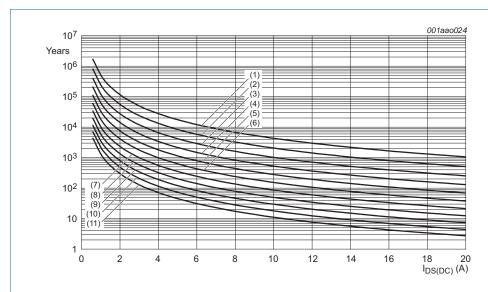


Table 8. Typical push-pull impedance

Simulated Z_i and Z_L device impedance; impedance info at $V_{DS} = 50 \text{ V}$ and $P_{L(AV)} = 120 \text{ W}$ (DVB-T).

	· · · · · · · · · · · · · · · · · · ·	20 2(11)	-
f	Z _i	Z _L	
MHz	Ω	Ω	
300	0.617 – j1.715	4.792 + j0.947	
325	0.635 – j1.355	4.707 + j0.994	
350	0.655 – j1.026	4.619 + j1.035	
375	0.677 – j0.721	4.528 + j1.069	
400	0.702 - j0.435	4.435 + j1.097	
425	0.731 – j0.164	4.340 + j1.118	
450	0.762 + j0.096	4.243 + j1.134	
475	0.798 + j0.347	4.147 + j1.143	
500	0.839 + j0.592	4.049 + j1.146	
525	0.884 + j0.833	3.952 + j1.144	
550	0.936 + j1.072	3.855 + j1.136	
575	0.995 + j1.310	3.759 + j1.123	
600	1.063 + j1.549	3.663 + j1.105	
625	1.141 + j1.791	3.569 + j1.083	
650	1.230 + j2.037	3.477 + j1.055	
675	1.334 + j2.289	3.385 + j1.024	
700	1.456 + j2.548	3.296 + j0.989	
725	1.599 + j2.814	3.209 + j0.949	
750	1.768 + j3.090	3.123 + j0.907	
775	1.971 + j3.376	3.039 + j0.861	
800	2.214 + j3.671	2.958 + j0.812	
825	2.510 + j3.975	2.879 + j0.761	
850	2.873 + j4.282	2.801 + j0.706	
875	3.320 + j4.584	2.726 + j0.650	
900	3.875 + j4.865	2.654 + j0.591	
925	4.562 + j5.095	2.583 + j0.530	
950	5.409 + j5.223	2.514 + j0.467	
975	6.426 + j5.166	2.448 + j0.403	
1000	7.587 + j4.807	2.384 + j0.337	

7.4 Reliability



TTF (0.1 % failure fraction).

The reliability at pulsed conditions can be calculated as follows: TTF (0.1 %) \times 1 / δ .

- (1) $T_i = 100 \, ^{\circ}C$
- (2) $T_j = 110 \, ^{\circ}C$
- (3) $T_j = 120 \, ^{\circ}C$
- (4) $T_i = 130 \, ^{\circ}C$
- (5) $T_i = 140 \, ^{\circ}\text{C}$
- (6) $T_j = 150 \, ^{\circ}C$
- (7) $T_j = 160 \, ^{\circ}C$
- (8) $T_j = 170 \, ^{\circ}C$
- (9) $T_j = 180 \, ^{\circ}C$
- (10) $T_j = 190 \,^{\circ}C$
- (11) $T_j = 200 \, ^{\circ}C$

Fig 9. BLF888B; BLF888BS electromigration (I_{DS(DC)}, total device)

8. Test information

Table 9. List of components

For test circuit, see Figure 10, Figure 11 and Figure 12.

Component	Description	Value		Remarks
B1, B2	semi rigid coax	25 Ω ; 49.5 mm		UT-090C-25 (EZ 90-25)
C1	multilayer ceramic chip capacitor	12 pF	[1]	
C2, C3, C4, C5, C6	multilayer ceramic chip capacitor	8.2 pF	[1]	
C7	multilayer ceramic chip capacitor	6.8 pF	[2]	
C8	multilayer ceramic chip capacitor	2.7 pF	[2]	
C9	multilayer ceramic chip capacitor	2.2 pF	[2]	
C10, C13, C14	multilayer ceramic chip capacitor	100 pF	[3]	
C11, C12	multilayer ceramic chip capacitor	10 pF	[2]	
C15, C16	multilayer ceramic chip capacitor	4.7 μF, 50 V		Kemet C1210X475K5RAC-TU or capacitor of same quality.
C17, C18, C23, C24	multilayer ceramic chip capacitor	100 pF	[2]	
C19, C20	multilayer ceramic chip capacitor	10 μF, 50 V		TDK C570X7R1H106KT000N or capacitor of same quality.
C21, C22	electrolytic capacitor	470 μF; 63 V		
C30	multilayer ceramic chip capacitor	10 pF	[4]	
C31	multilayer ceramic chip capacitor	9.1 pF	[4]	
C32	multilayer ceramic chip capacitor	3.9 pF	[4]	
C33, C34, C35	multilayer ceramic chip capacitor	100 pF	[4]	
C36, C37	multilayer ceramic chip capacitor	4.7 μF, 50 V		TDK C4532X7R1E475MT020U or capacitor of same quality.
L1	microstrip	-	[5]	(W \times L) 15 mm \times 13 mm
L2	microstrip	-	[5]	(W \times L) 5 mm \times 26 mm
L3, L32	microstrip	-	[5]	(W \times L) 2 mm \times 49.5 mm
L4	microstrip	-	[5]	(W \times L) 1.7 mm \times 3.5 mm
L5	microstrip	-	[5]	(W \times L) 2 mm \times 9.5 mm
L30	microstrip	-	[5]	(W \times L) 5 mm \times 13 mm
L31	microstrip	-	[5]	(W \times L) 2 mm \times 11 mm
L33	microstrip	-	[5]	(W \times L) 2 mm \times 3 mm
R1, R2	wire resistor	10 Ω		
R3, R4	SMD resistor	5.6 Ω		0805
R5, R6	wire resistor	100 Ω		
R7, R8	potentiometer	10 kΩ		
-				

^[1] American technical ceramics type 800R or capacitor of same quality.

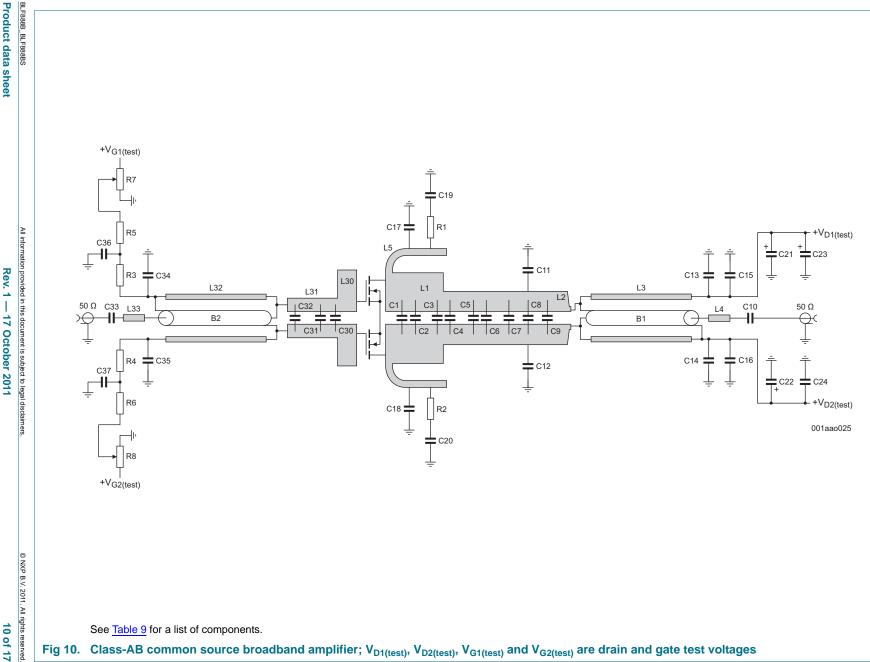
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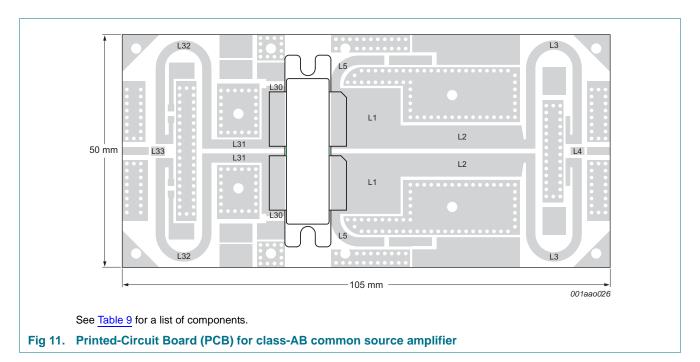
^[2] American technical ceramics type 800B or capacitor of same quality.

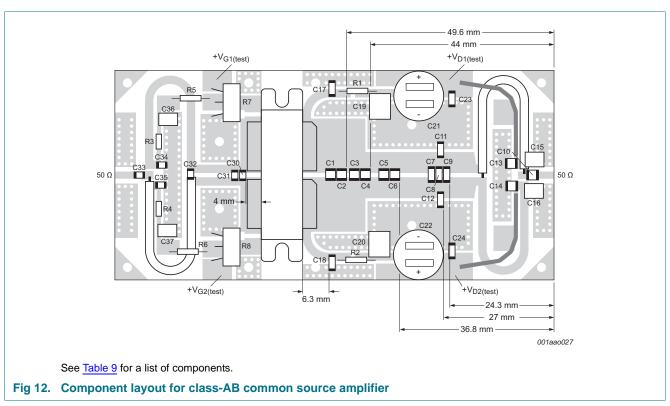
^[3] American technical ceramics type 180R or capacitor of same quality.

^[4] American technical ceramics type 100A or capacitor of same quality.

^[5] Printed-Circuit Board (PCB): Taconic RF35; ϵ_r = 3.5 F/m; height = 0.762 mm; Cu (top/bottom metallization); thickness copper plating = 35 μ m.







9. Package outline

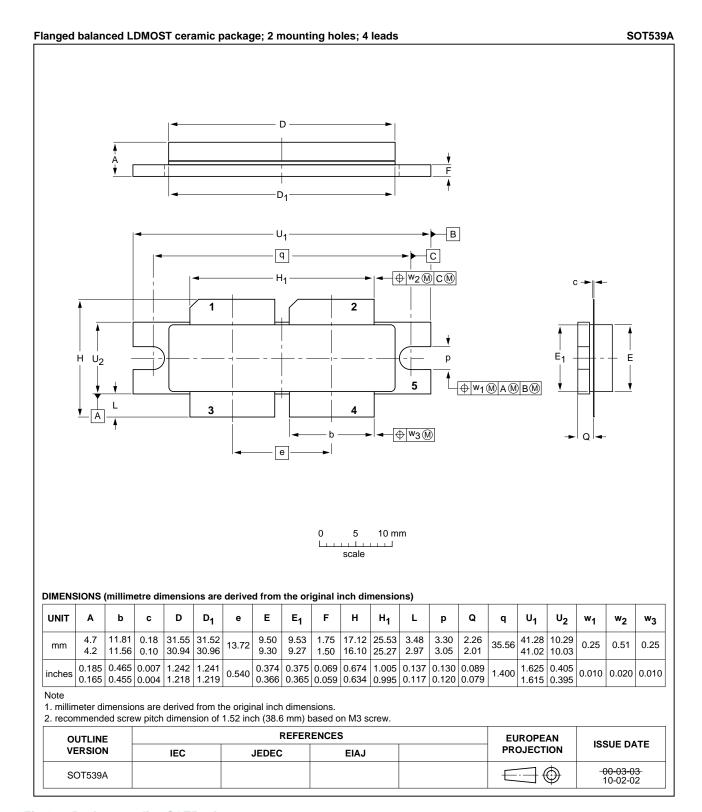


Fig 13. Package outline SOT539A

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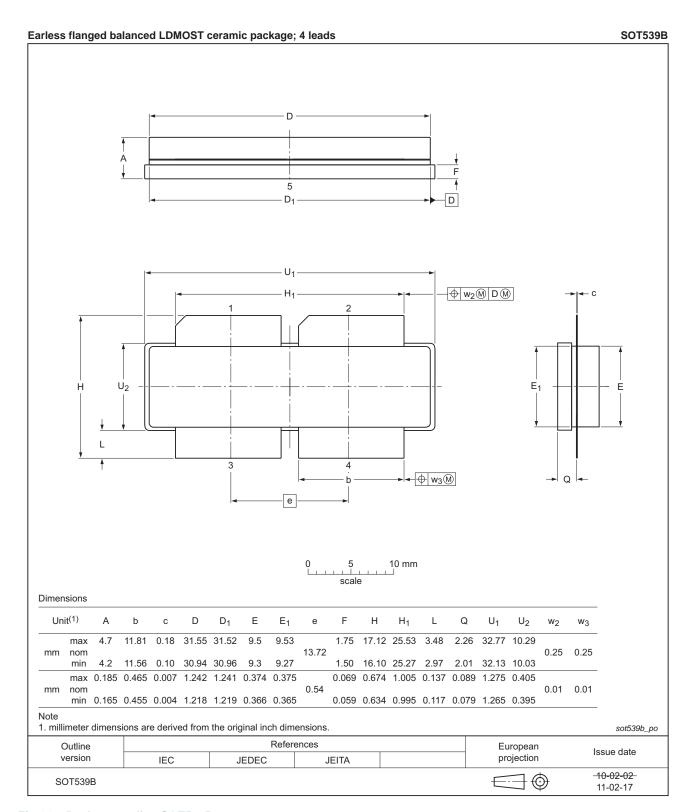


Fig 14. Package outline SOT539B

BLF888B_BLF888BS

10. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

11. Abbreviations

Table 10. Abbreviations

Acronym	Description
CCDF	Complementary Cumulative Distribution Function
DVB	Digital Video Broadcast
DVB-T	Digital Video Broadcast - Terrestrial
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
OFDM	Orthogonal Frequency Division Multiplexing
PAR	Peak-to-Average power Ratio
RF	Radio Frequency
SMD	Surface Mounted Device
TTF	Time-To-Failure
UHF	Ultra High Frequency
VSWR	Voltage Standing-Wave Ratio

12. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF888B_BLF888BS v.1	20111017	Product data sheet	-	-

13. Legal information

13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BLF888B_BLF888BS

BLF888B; **BLF888BS**

UHF power LDMOS transistor

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For sales office addresses, please send an email to: salesaddresses@nxp.com

15. Contents

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